Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/527,092	BEKANICH ET AL.	
Examiner	Art Unit	
/BINH K. TIEU/	2614	

	SEARCHED						
Cla	ss	Subclass	Date		Exa	Examiner	
45	5	405-409	12/30/2007		вкт		
Pr.		415 .	1	1	1		
37	9	114.01					
•]	114.03					
		114.16					
		114.17					
		114.2					
		115.01					
		121.01-04					
		122					
		127.01					
		127.06					
		144.01					
	V	144.08	•	V	•		

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
		•			
7					
		,			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
· .				
•				
	·			
,				
				